

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ENDO ET AL.	
		Examiner Bradley K. Smith	Art Unit 2894	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	W.R. RUNYAN and T.J. Schaffner, "Semiconductor Measurements and Instrumentation", New York: McGraw-Hill, 2nd edition, 1998, pp 99-100.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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